HARRIS SEMICONDUCTOR

CD74LCX16501

December 1997

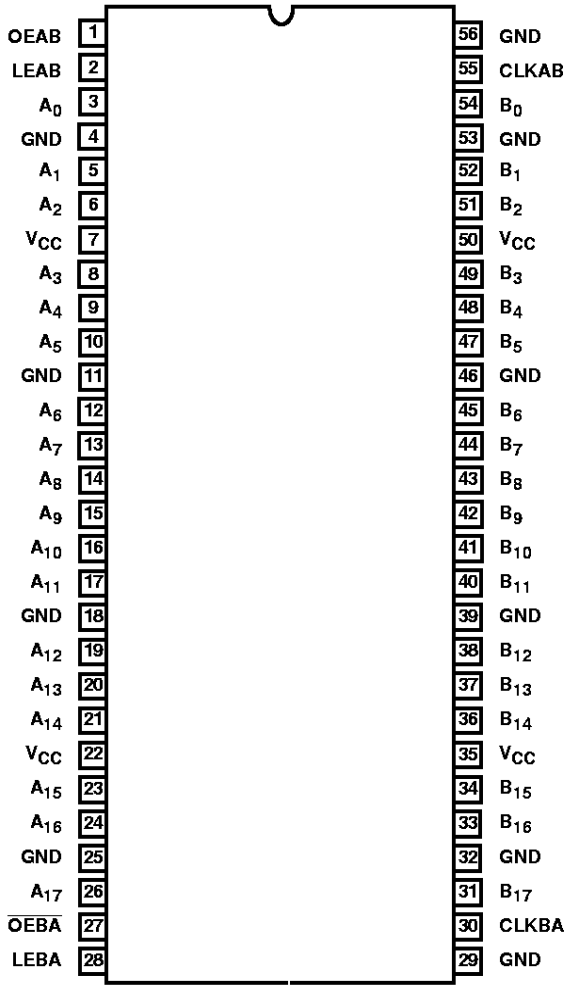
Fast CMOS 18-Bit Registered Transceiver

Features

- Advanced 0.6 micron CMOS Technology
- 5V Tolerant Inputs and Outputs
- Supports Live Insertion of PCBs
- 2.0V to 3.6V V_{CC} Supply Range
- Balanced 24mA Output Drive
- Low Ground Bounce Outputs
- ESD Protection Exceeds 2000V, HBM; 200V, MM
- Functionally Compatible with FCT3, LVC, LVT, and 74 Series Logic Families

Pinout

CD74LCX16501
(SSOP, TSSOP)
TOP VIEW



Description

The CD74LCX16501 is an 18-bit registered bus transceiver designed with D-type latches and flip-flops to allow data flow in transparent, latched, and clocked modes. The Output Enable (OEAB and $\overline{OEBA}$), Latch Enable (LEAB and LEBA) and Clock (CLKAB and CLKBA) inputs control the data flow in each direction. When LEAB is HIGH, the device operates in transparent mode for A-to-B data flow. When LEAB is LOW, the A data is latched if CLKAB is held at a HIGH or LOW logic level. The A bus data is stored in the latch/flip-flop on the LOW-to-HIGH transition of CLKAB, if LEAB is LOW. OEAB performs the output enable function on the B port. Data flow from B port to A port is similar using $\overline{OEBA}$, LEBA and CLKBA. This high-speed, low power device offers a flow-through organization for ease of board layout.

The CD74LCX16501 can be driven from either 3.3V or 5.0V devices allowing this device to be used as a translator in a mixed 3.3V/5.0V system.

Ordering Information

PART NUMBER	TEMP. RANGE (^oC)	PACKAGE	PKG. NO.
CD74LCX16501MT	-40 to 85	56 Ld TSSOP	M56.240-P
CD74LCX16501SM	-40 to 85	56 Ld SSOP	M56.300-P

NOTE: When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.

CAUTION: These devices are sensitive to electrostatic discharge. Users should follow proper IC Handling Procedures.

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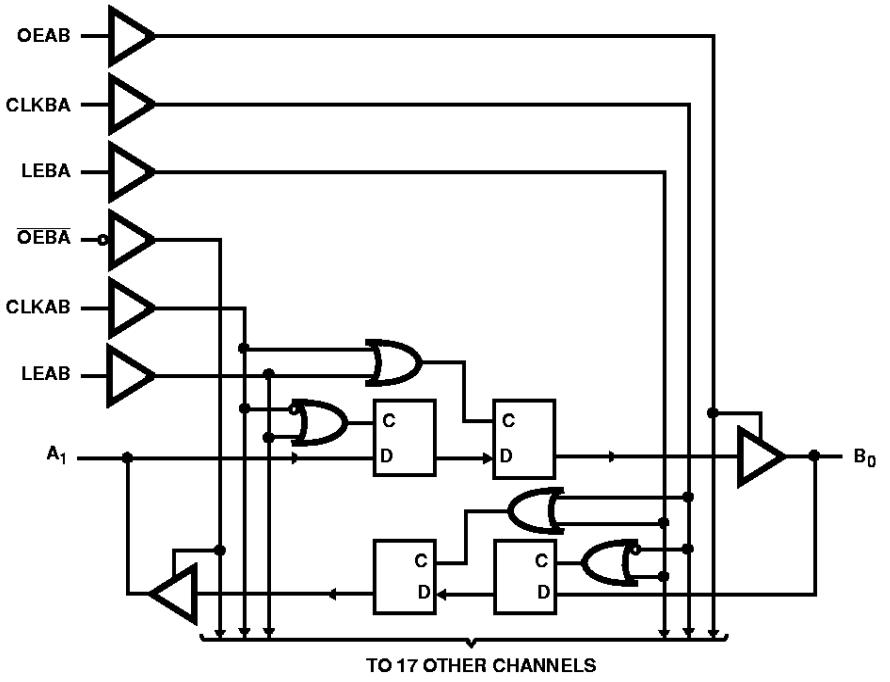
File Number **4437**

Functional Block Diagram



TRUTH TABLE (NOTES 1, 4)

INPUTS				OUTPUTS
OEAB	**LEAB**	**CLKAB**	**A_X**	**B_X**
L	X	X	X	Z
H	H	X	L	L
H	H	X	H	H
H	L	↑	L	L
H	L	↑	H	H
H	L	L	X	B (Note 2)
H	L	H	X	B (Note 3)

NOTES:

1. A-to-B data flow is shown. B-to-A data flow is similar but uses $\overline{OEBA}$, LEBA, and CLKBA.
2. Output level before the indicated steady-state input conditions were established.
3. Output level before the indicated steady-state input conditions were established, provided that CLKAB was HIGH before LEAB went LOW.
4. H = High Voltage Level; L = Low Voltage Level; Z = High Impedance; ↑ = LOW-to-HIGH Transition

Pin Descriptions

PIN NAME	DESCRIPTION
OEAB	A-to-B Output Enable Input
$\overline{OEBA}$	B-to-A Output Enable Input (Active LOW)
LEAB	A-to-B Latch Enable Input
LEBA	B-to-A Latch Enable Input
CLKAB	A-to-B Clock Input
CLKBA	B-to-A Clock Input
A_X	A-to-B Data Inputs or B-to-A Three-State Outputs
B_X	B-to-A Data Inputs or A-to-B Three-State Outputs
GND	Ground
V_{CC}	Power

Absolute Maximum Ratings

DC Input Voltage . . . . . -0.5V to 7.0V
DC Output Current 120mA

Operating Conditions

Temperature Range . . . . . -40°C to 85°C
Supply Voltage to Ground Potential
Inputs and V_{CC} Only. . . . . -0.5V to 7.0V
Supply Voltage, V_{CC}
Operating . . . . . 2.0V (Min), 3.6V (Max)
Data Retention . . . . . 1.5V (Min), 3.6V (Max)
Supply Voltage to Ground Potential
Outputs and D/O Only. . . . . -0.5V to 7.0V

Thermal Information

Thermal Resistance (Typical, Note 5)	θ_{JA} (°C/W)
TSSOP Package	85
SSOP Package	70

Maximum Junction Temperature . . . . . 150°C
Maximum Storage Temperature Range . . . . . -65°C to 150°C
Maximum Lead Temperature (Soldering 10s) . . . . . 300°C
(Lead Tips Only)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

5. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications

PARAMETER	SYMBOL	(NOTE 6) TEST CONDITIONS		MIN	(NOTE 7) TYP	MAX	UNITS
DC ELECTRICAL SPECIFICATIONS Over the Operating Range, T_A = -40°C to 85°C, V_{CC} = 2.7V to 3.6V							
Input HIGH Voltage	V_{IH}	Guaranteed Logic HIGH Level		2.0	-	-	V
Input LOW Voltage (Input and I/O Pins)	V_{IL}	Guaranteed Logic LOW Level		-	-	0.8	V
Output HIGH Voltage	V_{OH}	V_{CC} = 2.7V to 3.6V	I_{OH} = -0.1mA	V_{CC} - 0.2	-	-	V
		V_{CC} = 2.7V	I_{OH} = -12mA	2.2	-	-	V
		V_{CC} = 3.0V	I_{OH} = -18mA	2.4	-	-	V
			I_{OH} = -24mA	2.2	-	-	V
Output LOW Voltage	V_{OL}	V_{CC} = 2.7V to 3.6V	I_{OL} = 0.1mA	-	-	0.2	V
		V_{CC} = 2.7V	I_{OL} = 12mA	-	-	0.4	V
		V_{CC} = 3V	I_{OL} = 16mA	-	-	0.4	V
			I_{OL} = 24mA	-	-	0.55	V
Clamp Diode Voltage	V_{IK}	V_{CC} = Min, I_{IN} = -18mA		-	-0.7	-1.2	V
Input Current	I_I	V_{CC} = 2.7V to 3.6V	0 ≤ V_I ≤ 5.5V	-	-	±5	µA
High Impedance Output Current (Three-State)	I_{OZ}	V_{CC} = 2.7V to 3.6V	0 ≤ V_O ≤ 5.5V V_I = V_{IH} or V_{IL}	-	-	±5	µA
Power Down Disable	I_{OFF}	V_{CC} = 0V	V_{IN} or V_{OUT} ≤ 5.5V	-	-	10	µA
Quiescent Power Supply Current	I_{CC}	V_{CC} = Max	V_{IN} = GND or V_{CC}	-	0.1	10	µA
Quiescent Power Supply Current TTL Inputs HIGH	ΔI_{CC}	V_{CC} = Max	V_{IN} = V_{CC} - 0.6V (Note 8)	-	-	500	µA

Electrical Specifications (Continued)

PARAMETER	SYMBOL	(NOTE 6) TEST CONDITIONS	MIN	(NOTE 7) TYP	MAX	UNITS
CAPACITANCE						
Input Capacitance (Note 9)	C_{IN}	V_{CC} = Open, V_{IN} = 0V or V_{CC}	-	7	-	pF
Output Capacitance (Note 9)	C_{OUT}	V_{CC} = 3.3V, V_{IN} = 0V or V_{CC}	-	8	-	pF
Power Dissipation Capacitance (Note 10)	C_{PD}	V_{CC} = 3.3V, V_{IN} = 0V or V_{CC}, f = 10MHz	-	20	-	pF

Switching Specifications Over Operating Range

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} = 3.3V ±0.3V		V_{CC} = 2.7V		UNITS
			MIN	MAX	MIN	MAX	
Maximum Clock Frequency	f_{MAX}	C_L = 50pF, R_L = 500Ω	170	-	-	-	MHz
Propagation Delay, Bus to Bus	t_{PHL}, t_{PLH}	C_L = 50pF, R_L = 500Ω	1.5	6.0	1.5	7.0	ns
Propagation Delay, Clock to Bus	t_{PHL}, t_{PLH}	C_L = 50pF, R_L = 500Ω	1.5	6.5	1.5	7.5	ns
Propagation Delay, LE to Bus	t_{PHL}, t_{PLH}	C_L = 50pF, R_L = 500Ω	1.5	6.5	1.5	7.5	ns
Output Enable Time	t_{PZL}, t_{PZH}	C_L = 50pF, R_L = 500Ω	1.5	7.5	1.5	8.5	ns
Output Disable Time (Note 13)	t_{PLZ}, t_{PHZ}	C_L = 50pF, R_L = 500Ω	1.5	6.0	1.5	7.0	ns
Setup Time	t_S	C_L = 50pF, R_L = 500Ω	2.5	-	2.5	-	ns
Hold Time	t_H	C_L = 50pF, R_L = 500Ω	1.5	-	1.5	-	ns
Pulse Width (Note 13)	t_W	C_L = 50pF, R_L = 500Ω	3.0	-	3.0	-	ns
Output to Output Skew (Note 14)	$t_{SK(O)}$	C_L = 50pF, R_L = 500Ω	-	1.0	-	-	ns

Dynamic Switching Characteristics $T_A = 25^oC$

PARAMETER	SYMBOL	(NOTE 15) TEST CONDITIONS	TYP	UNITS
Dynamic LOW Peak Voltage	V_{OLP}	V_{CC} = 3.3V, C_L = 50pF, V_{IH} = 3.3V, V_{IL} = 0V	0.8	V
Dynamic LOW Valley Voltage	V_{OLV}	V_{CC} = 3.3V, C_L = 50pF, V_{IH} = 3.3V, V_{IL} = 0V	0.8	V

NOTES:

6. For conditions shown as Max or Min, use appropriate value specified under Electrical Specifications for the applicable device type.
7. Typical values are at V_{CC} = 3.3V, 25°C ambient and maximum loading.
8. Per TTL driven input; all other inputs at V_{CC} or GND.
9. This parameter is determined by device characterization but is not production tested.
10. C_{PD} determines the no-load dynamic power consumption per latch. It is obtained by the following relationship: P_D (total power per latch) = V_{CC}^2 f_i (C_{PD} + C_L) where f_i = input frequency, C_L = output load capacitance, V_{CC} = supply range.
11. See test circuit and waveforms.
12. Minimum limits are guaranteed but not tested on Propagation Delays.
13. This parameter is guaranteed but not production tested.
14. Skew between any two outputs, of the same package, switching in the same direction. This parameter is guaranteed by design.
15. Measured with n-1 outputs switching from High-to-Low or Low-to-High. The remaining output is measured in the LOW state.